

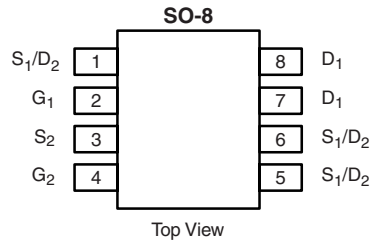
Dual N-Channel 30-V (D-S) MOSFET with Schottky Diode

PRODUCT SUMMARY

	V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, e}	Q _g (Typ.)
Channel-1	30	0.0156 at V _{GS} = 10 V	8.0	7.3
		0.019 at V _{GS} = 4.5 V	8.0	
Channel-2	30	0.0156 at V _{GS} = 10 V	8.0	7.3
		0.019 at V _{GS} = 4.5 V	8.0	

SCHOTTKY PRODUCT SUMMARY

V _{DS} (V)	V _{SD} (V) Diode Forward Voltage	I _F (A) ^a
30	0.51 V at 1.0 A	2.0



FEATURES

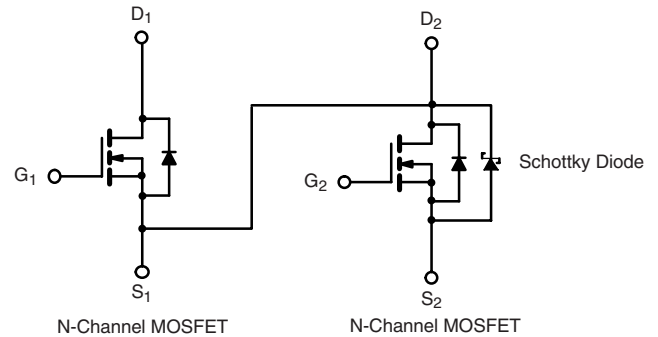
- Halogen-free According to IEC 61249-2-21 Definition
- LITTLE FOOT[®] Plus Schottky
- PWM Optimized
- 100 % R_g Tested
- 100 % UIS Tested
- Compliant to RoHS Directive 2002/95/EC



RoHS
COMPLIANT
HALOGEN
FREE
Available

APPLICATIONS

- Notebook Logic dc-to-dc
- Low Current dc-to-dc



ABSOLUTE MAXIMUM RATINGS T_A = 25 °C, unless otherwise noted

Parameter	Symbol	Channel-1	Channel-2	Unit
Drain-Source Voltage	V _{DS}	30	30	V
Gate-Source Voltage	V _{GS}	± 20	± 20	
Continuous Drain Current (T _J = 150 °C)	I _D	8.0 ^e	8.0 ^e	A
		7.1	7.1	
		7.5 ^{b, c}	7.5 ^{b, c}	
		5.8 ^{b, c}	5.8 ^{b, c}	
Pulsed Drain Current (10 μs Pulse Width)	I _{DM}	30	30	
Source-Drain Current Diode Current	I _S	2.6	2.6	
		1.8 ^{b, c}	1.8 ^{b, c}	
Pulsed Source-Drain Current	I _{SM}	30	30	
Single Pulse Avalanche Current	I _{AS}	10	10	
Single Pulse Avalanche Energy	E _{AS}	5	5	mJ
Maximum Power Dissipation	P _D	2.9	2.9	W
		1.8	1.8	
		2 ^{b, c}	2 ^{b, c}	
		1.2 ^{b, c}	1.2 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150		°C

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Channel-1		Channel-2		Unit
Maximum Junction-to-Ambient ^{b, d}	R _{thJA}	Typ.	Max.	Typ.	Max.	°C/W
Maximum Junction-to-Foot (Drain)	R _{thJF}	35	43	35	43	

Notes:

a. Based on T_C = 25 °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 110 °C/W (Channel-1) and 110 °C/W (Channel-2).

e. Package limited.

SPECIFICATIONS T _J = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions		Min.	Typ. ^a	Max.	Unit
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 1 mA	Ch-1	30			V
		V _{GS} = 0 V, I _D = 1 mA	Ch-2	30			
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	I _D = 250 μA	Ch-1		32		mV/°C
V _{GS(th)} Temperature Coefficient	ΔV _{GS(th)} /T _J	I _D = 250 μA	Ch-1		- 6		
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 1 mA	Ch-1	1		3	V
		V _{DS} = V _{GS} , I _D = 1 mA	Ch-2	1		3	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 20 V	Ch-1			100	nA
		V _{DS} = 0 V, V _{GS} = ± 20 V	Ch-2			100	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V	Ch-1			0.001	mA
		V _{DS} = 30 V, V _{GS} = 0 V	Ch-2		0.016	0.10	
		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 100 °C	Ch-1			0.025	
		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 100 °C	Ch-2		1.1	10	
On-State Drain Current ^b	I _{D(on)}	V _{DS} = 5 V, V _{GS} = 10 V	Ch-1	20			A
		V _{DS} = 5 V, V _{GS} = 10 V	Ch-2	20			
Drain-Source On-State Resistance ^b	R _{DS(on)}	V _{GS} = 10 V, I _D = 8 A	Ch-1		0.0156		Ω
		V _{GS} = 10 V, I _D = 8 A	Ch-2		0.0156		
		V _{GS} = 4.5 V, I _D = 5 A	Ch-1		0.019		
		V _{GS} = 4.5 V, I _D = 5 A	Ch-2		0.019		
Forward Transconductance ^b	g _{fs}	V _{DS} = 15 V, I _D = 8 A	Ch-1		29		S
		V _{DS} = 15 V, I _D = 8 A	Ch-2		29		
Dynamic ^a							
Input Capacitance	C _{iss}	Channel-1 V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz	Ch-1		950		pF
			Ch-2		950		
Output Capacitance	C _{oss}	Channel-2 V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz	Ch-1		155		
			Ch-2		185		
Reverse Transfer Capacitance	C _{rss}	Channel-1 V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz	Ch-1		65		
			Ch-2		65		
Total Gate Charge	Q _g	V _{DS} = 15 V, V _{GS} = 10 V, I _D = 8 A	Ch-1		16.5	25	nC
		V _{DS} = 15 V, V _{GS} = 10 V, I _D = 8 A	Ch-2		16.5	25	
		Channel-1 V _{DS} = 15 V, V _{GS} = 4.5 V, I _D = 8 A	Ch-1		7.3	11	
			Ch-2		7.3	11	
Gate-Source Charge	Q _{gs}	Channel-2 V _{DS} = 15 V, V _{GS} = 4.5 V, I _D = 8 A	Ch-1		2.7		
			Ch-2		2.7		
Gate-Drain Charge	Q _{gd}		Ch-1		2.1		
			Ch-2		2.1		
Gate Resistance	R _g	f = 1 MHz	Ch-1	0.2	1.2	2.4	Ω
			Ch-2	0.2	1.2	2.4	

Notes:

a. Guaranteed by design, not subject to production testing.

b. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.

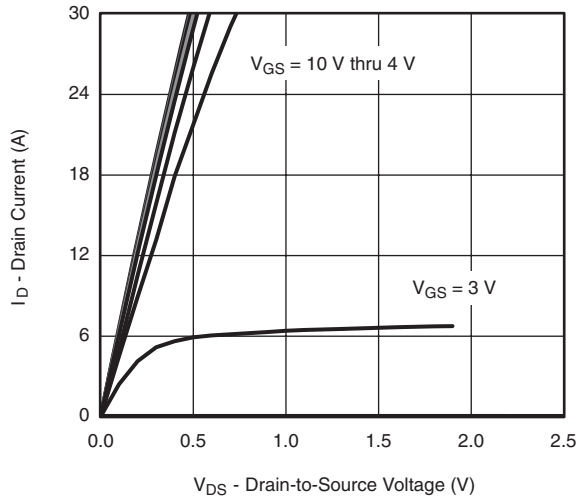
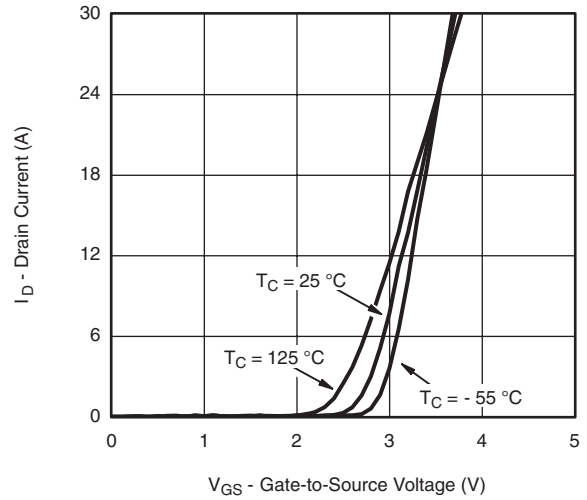
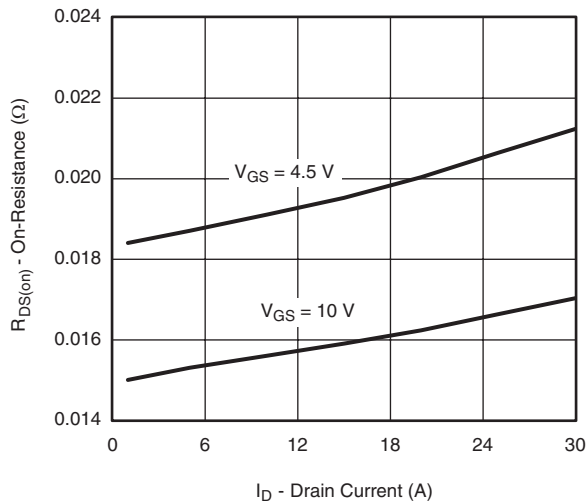
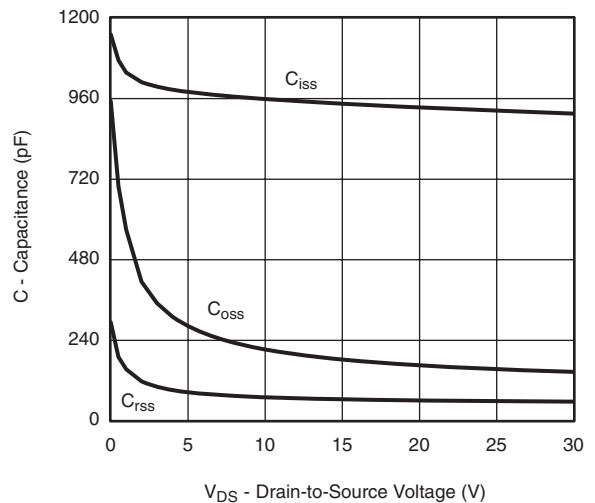
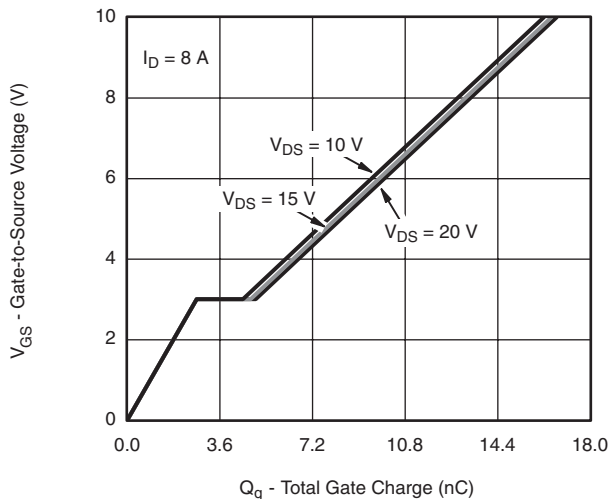
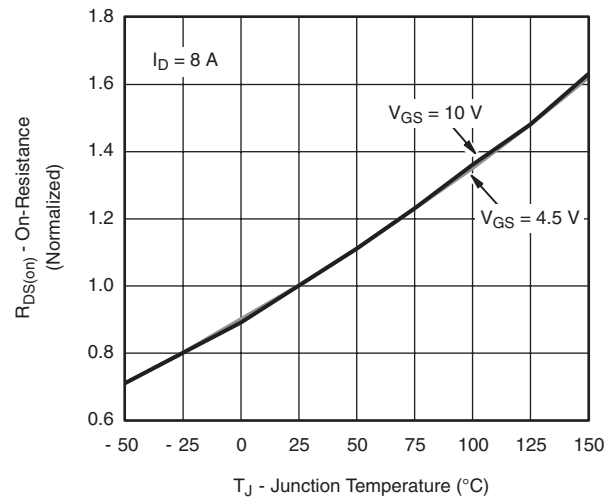
SPECIFICATIONS T _J = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Typ. ^a	Max.	Unit	
Dynamic ^a							
Turn-On Delay Time	t _{d(on)}	Channel-1 V _{DD} = 15 V, R _L = 3 Ω I _D ≡ 5 A, V _{GEN} = 10 V, R _g = 1 Ω	Ch-1		9	18	ns
			Ch-2		10	20	
Rise Time	t _r		Ch-1		11	20	
			Ch-2		10	20	
Turn-Off Delay Time	t _{d(off)}	Ch-1		18	35		
		Ch-2		18	35		
Fall Time	t _f	Ch-1		8	16		
		Ch-2		9	18		
Turn-On Delay Time	t _{d(on)}	Channel-1 V _{DD} = 15 V, R _L = 3 Ω I _D ≡ 5 A, V _{GEN} = 4.5 V, R _g = 1 Ω	Ch-1		17	35	
			Ch-2		17	35	
Rise Time	t _r		Ch-1		12	24	
			Ch-2		12	24	
Turn-Off Delay Time	t _{d(off)}	Ch-1		18	35		
		Ch-2		19	35		
Fall Time	t _f	Ch-1		10	20		
		Ch-2		10	20		
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	Ch-1			2.6	A
			Ch-2			2.6	
Pulse Diode Forward Current ^a	I _{SM}		Ch-1			30	
			Ch-2			30	
Body Diode Voltage	V _{SD}	I _S = 1 A	Ch-1		0.74	1.1	V
			Ch-2		0.46	0.51	
Body Diode Reverse Recovery Time	t _{rr}	Channel-1 I _F = 5 A, dI/dt = 100 A/μs, T _J = 25 °C	Ch-1		17	34	ns
			Ch-2		17	34	
Body Diode Reverse Recovery Charge	Q _{rr}		Ch-1		9	18	nC
			Ch-2		7	14	
Reverse Recovery Fall Time	t _a	Channel-2 I _F = 5 A, dI/dt = 100 A/μs, T _J = 25 °C	Ch-1		10		ns
			Ch-2		9		
Reverse Recovery Rise Time	t _b		Ch-1		7		
			Ch-2		8		

Notes:

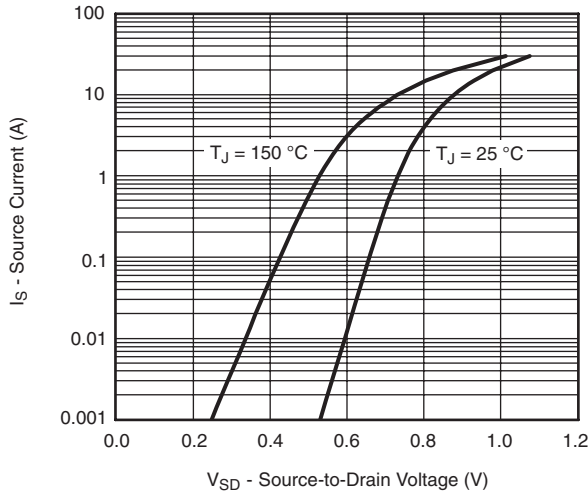
a. Guaranteed by design, not subject to production testing.

b. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.

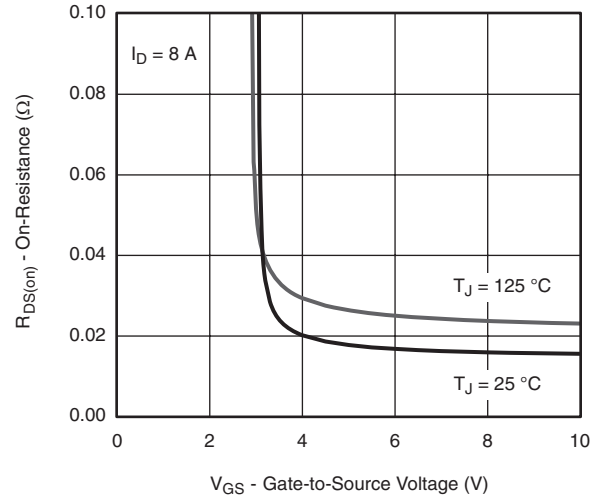
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Output Characteristics

Transfer Characteristics

On-Resistance vs. Drain Current

Capacitance

Gate Charge

On-Resistance vs. Junction Temperature

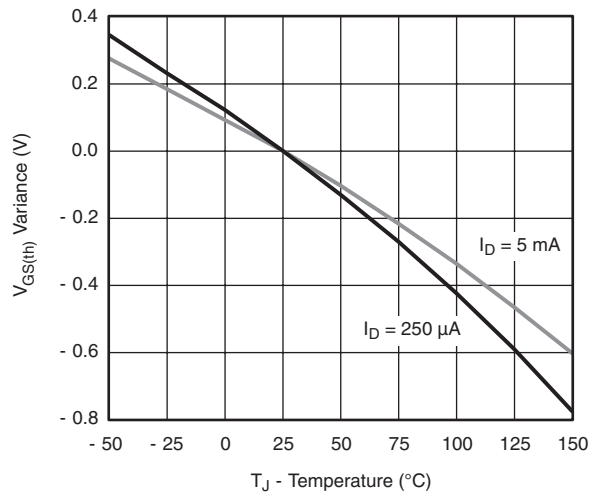
CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



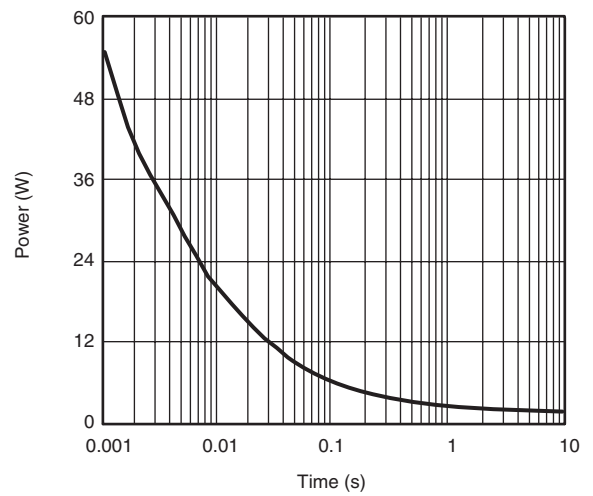
Source-Drain Diode Forward Voltage



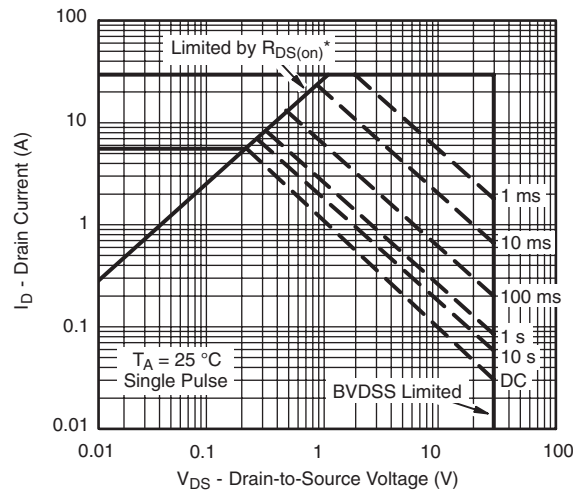
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage



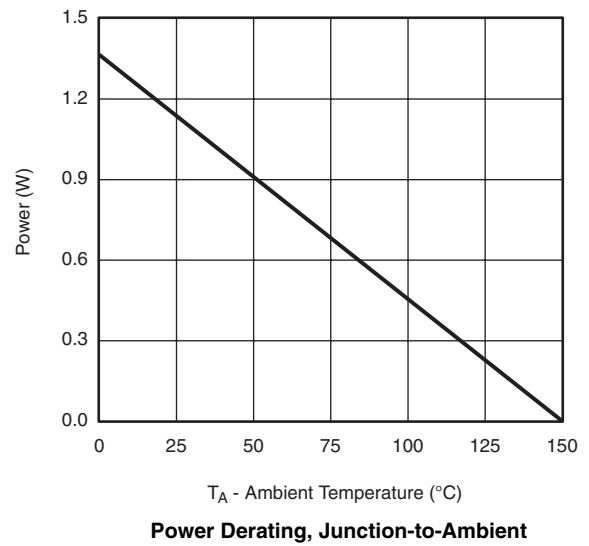
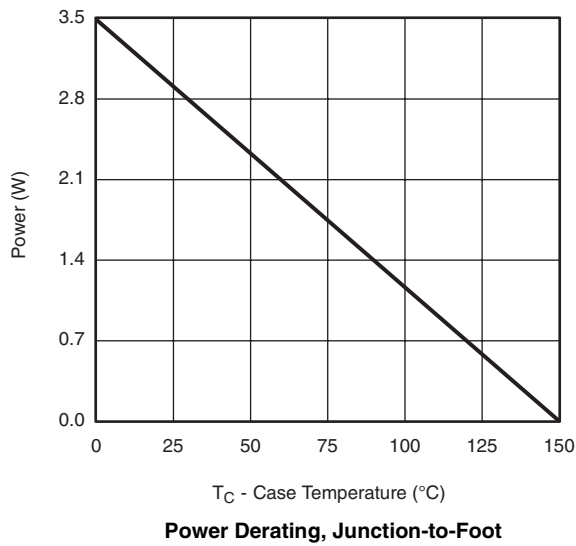
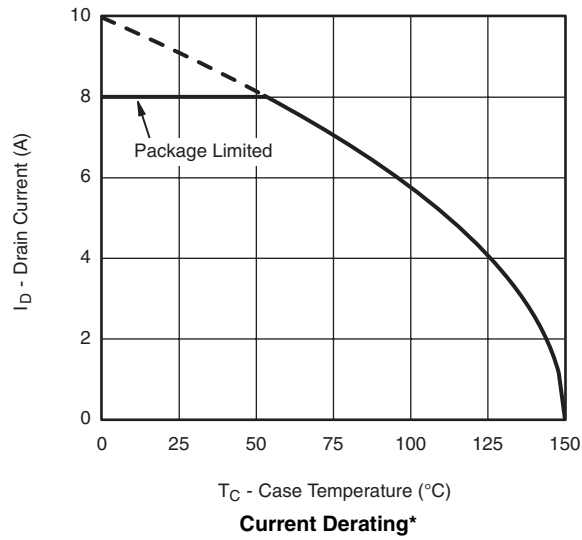
Single Pulse Power, Junction-to-Ambient



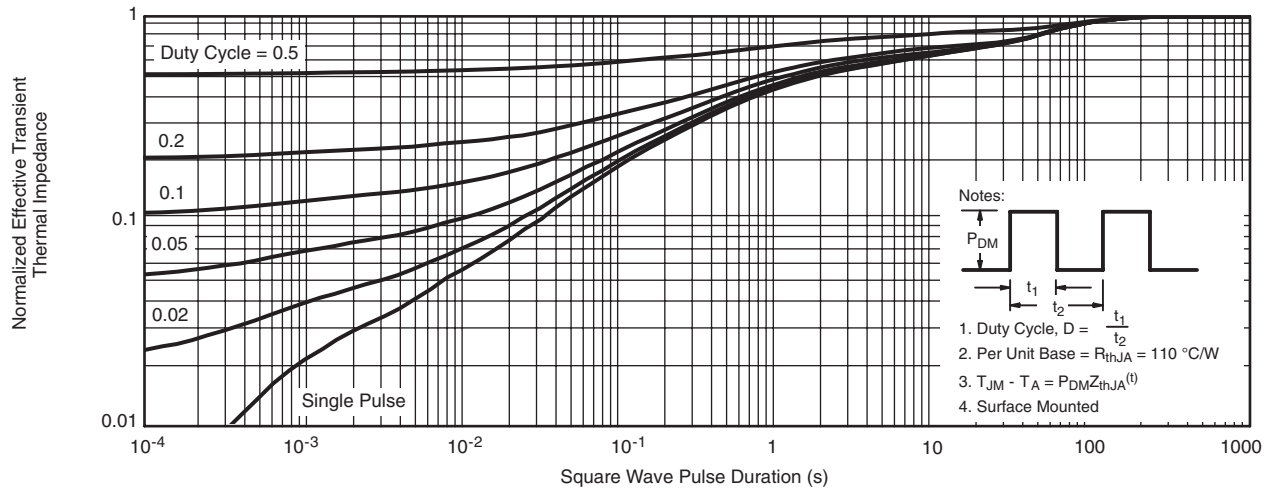
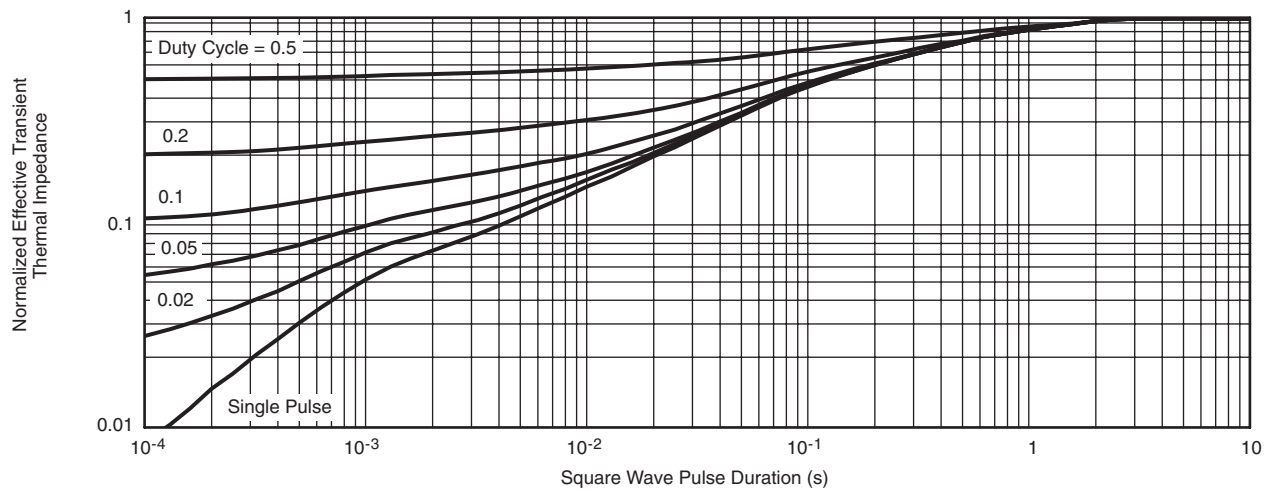
* $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient

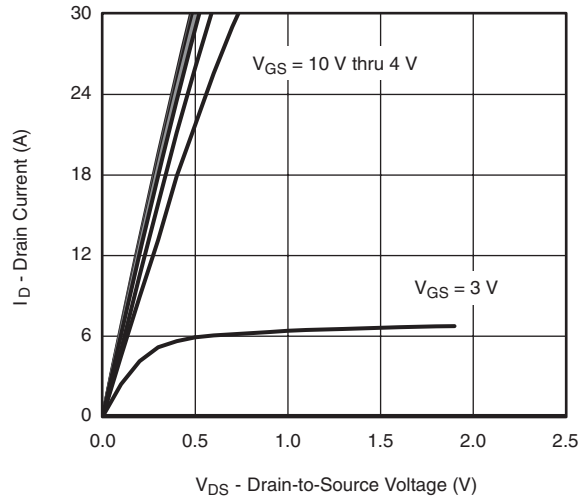
CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



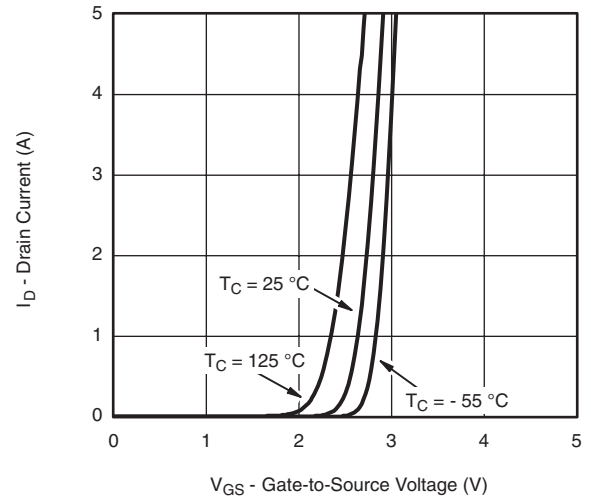
* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Normalized Thermal Transient Impedance, Junction-to-Ambient

Normalized Thermal Transient Impedance, Junction-to-Foot

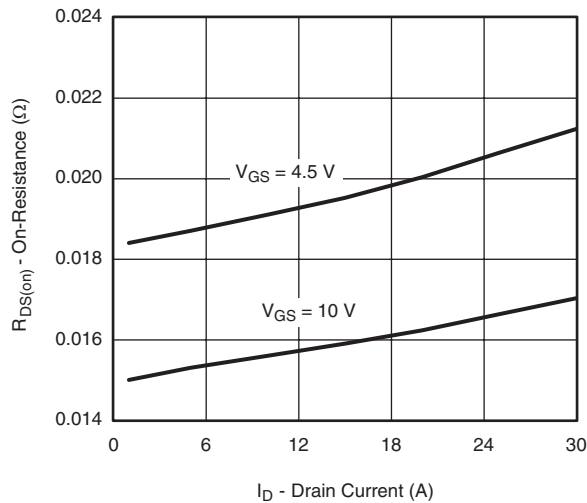
CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



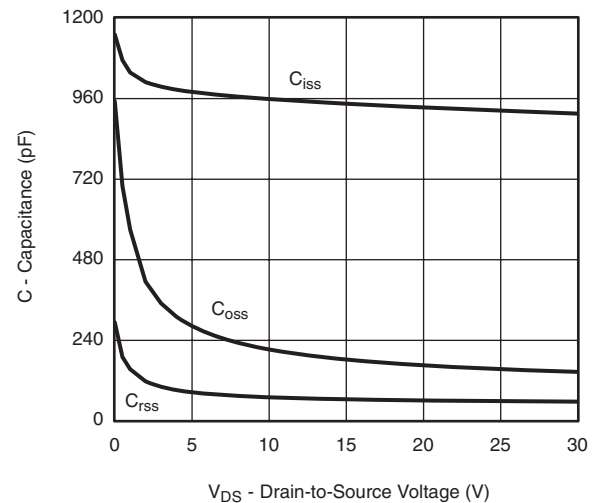
Output Characteristics



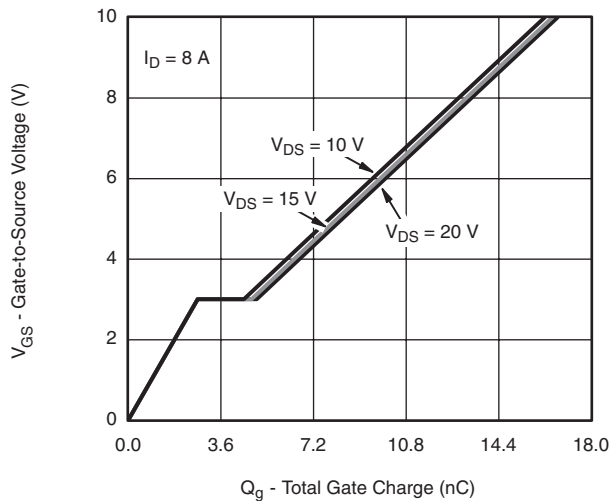
Transfer Characteristics



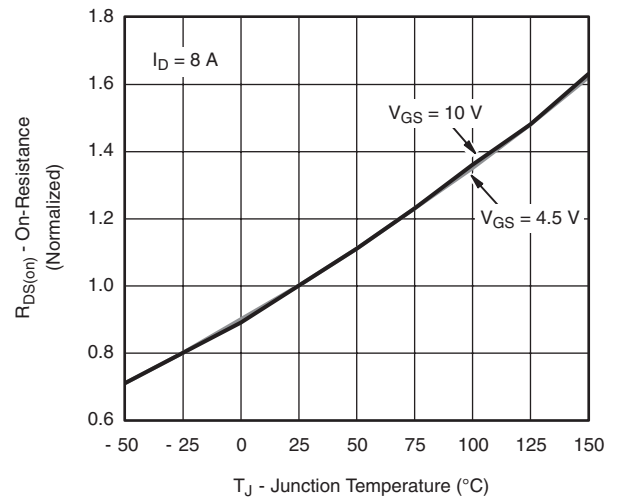
On-Resistance vs. Drain Current



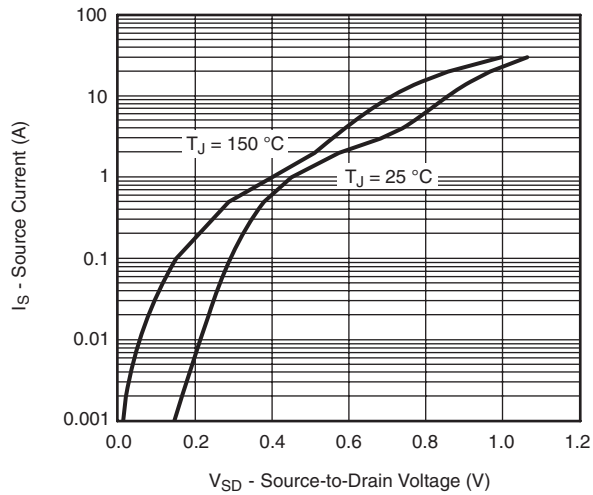
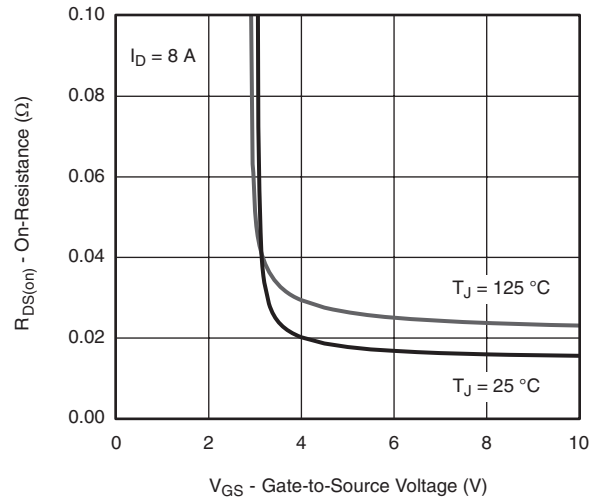
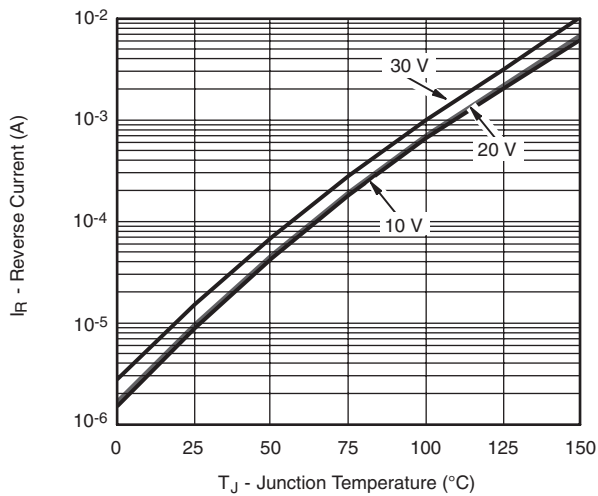
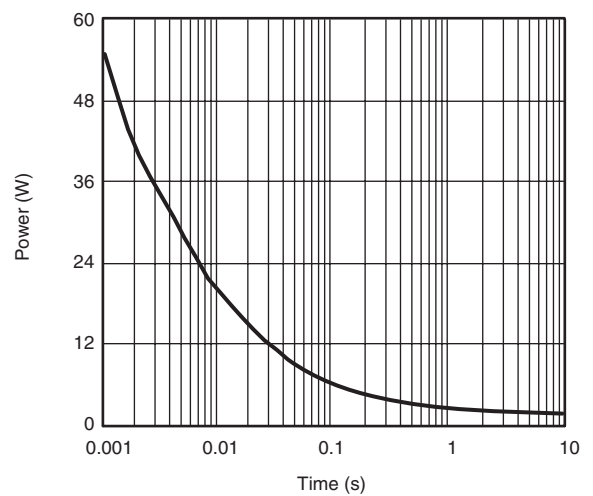
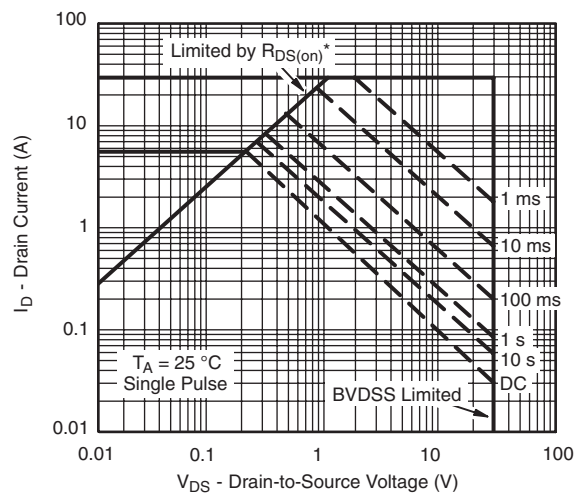
Capacitance



Gate Charge



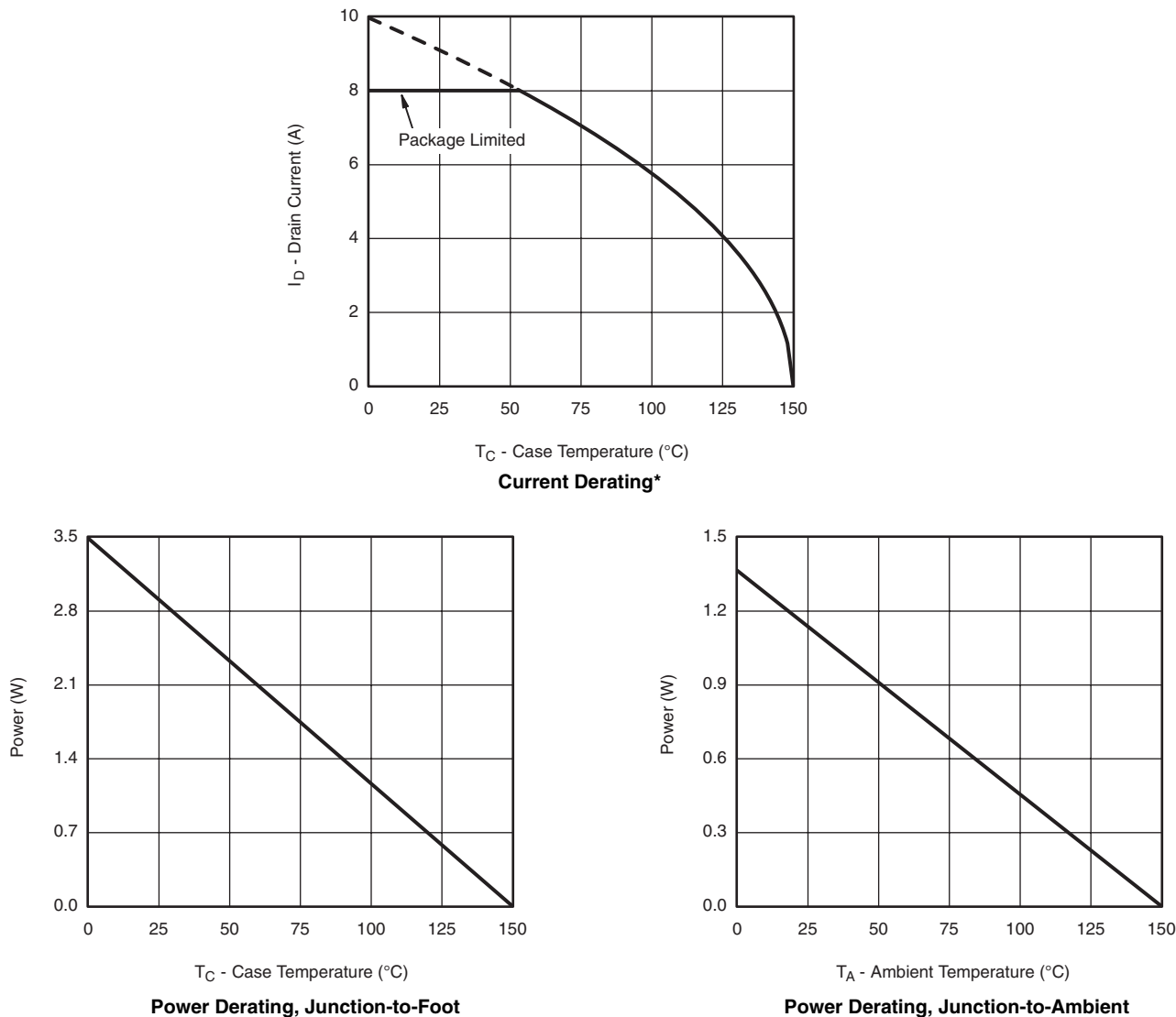
On-Resistance vs. Junction Temperature

CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source Voltage

Reverse Current (Schottky)

Single Pulse Power, Junction-to-Ambient


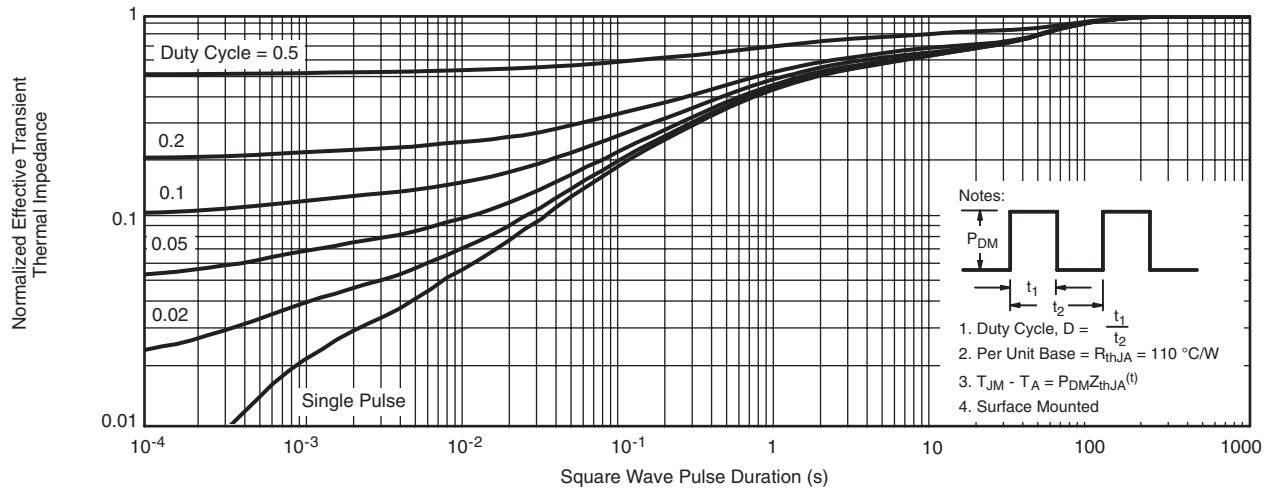
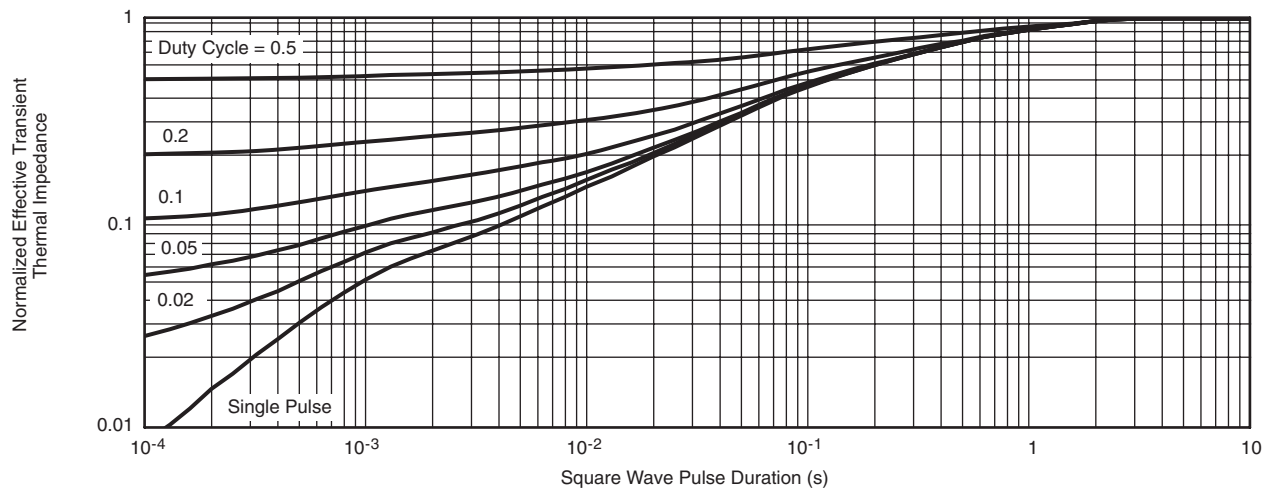
* $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient

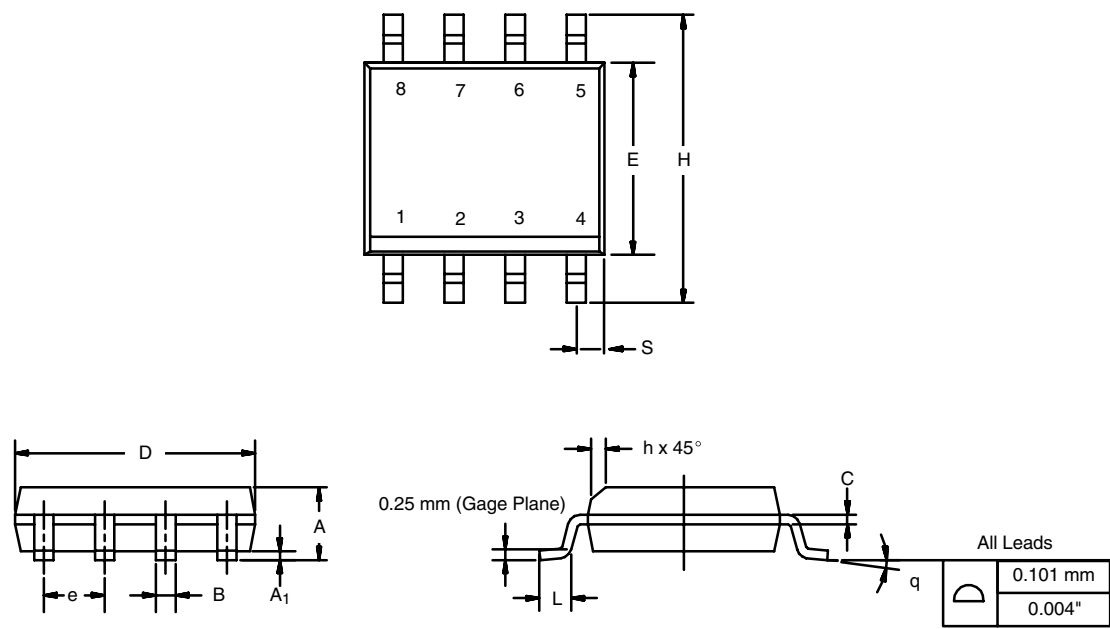
CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



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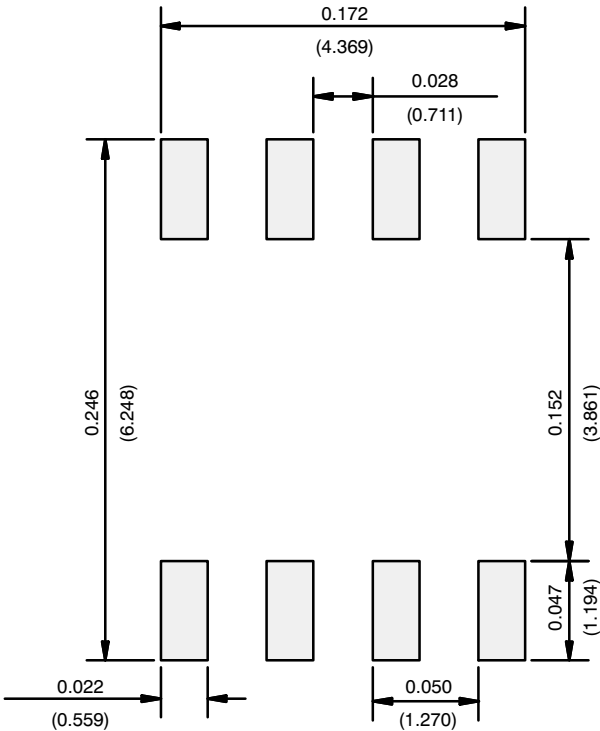
CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Normalized Thermal Transient Impedance, Junction-to-Ambient

Normalized Thermal Transient Impedance, Junction-to-Foot

SOIC (NARROW): 8-LEAD
JEDEC Part Number: MS-012



DIM	MILLIMETERS		INCHES	
	Min	Max	Min	Max
A	1.35	1.75	0.053	0.069
A ₁	0.10	0.20	0.004	0.008
B	0.35	0.51	0.014	0.020
C	0.19	0.25	0.0075	0.010
D	4.80	5.00	0.189	0.196
E	3.80	4.00	0.150	0.157
e	1.27 BSC		0.050 BSC	
H	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.020
L	0.50	0.93	0.020	0.037
q	0°	8°	0°	8°
S	0.44	0.64	0.018	0.026
ECN: C-06527-Rev. I, 11-Sep-06				
DWG: 5498				

RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads
Dimensions in Inches/(mm)

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